

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: January 29, 2004			ATTY DOCKET NO. 2004-0145		SERIAL NO. NEW 60/766,565		
			APPLICANT Yoko SUZUKI et al.				
			FILING DATE January 29, 2004		GROUP 1724		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>My</i>	AA	5,346,518	9/1994	Baseman et al.			
	AB	6,040,680	3/2000	Toya et al.			
	AC	5,380,503	1/1995	Fujii et al.			
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	AE	4,967,295	10/1990	Yamauchi et al.			
	AF	6,436,849	8/2002	Hasunuma et al.			
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<i>My</i>	AJ	2000-174109	6/2000	JP			
	AK	9-29020	2/1997	JP			
	AL	6-291177	10/1994	JP			
	AM	7-94577	4/1995	JP			
	AN	617573A		EP			
	AO	69401023C		DE			
	AP	11-195699	7/1999	JP			
<i>My</i>	AO	2000-223554	8/2000	JP			
<i>My</i>	AR	11-314703	11/1999	JP			
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<i>My</i>	AS	Shoko ITO et al., "Wafer ambient control for Agile FAB", 0-7803-6731-6/01/\$10.00©2001 IEEE, pgs. 121-124.					
EXAMINER	<i>Minh Phan</i>			DATE CONSIDERED	<i>6/2/05</i>		

FORM PTO 1449 (modified)			ATTY DOCKET NO. 2004-0145	SERIAL NO. NEW	10/766,585		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			APPLICANT Yoko SUZUKI et al.				
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<i>LL</i>	AA	5,749,469	5/1998	Williams			
<i>LL</i>	AB	6,364,922	4/2002	Tanaka et al.			
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	AD	381356B		TW			
	AE	0560379A1	9/1993	EP			
	AF	6-29373	2/1994	JP			
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EXAMINER	<i>Mark Haitham</i>			DATE CONSIDERED	26/02/05		